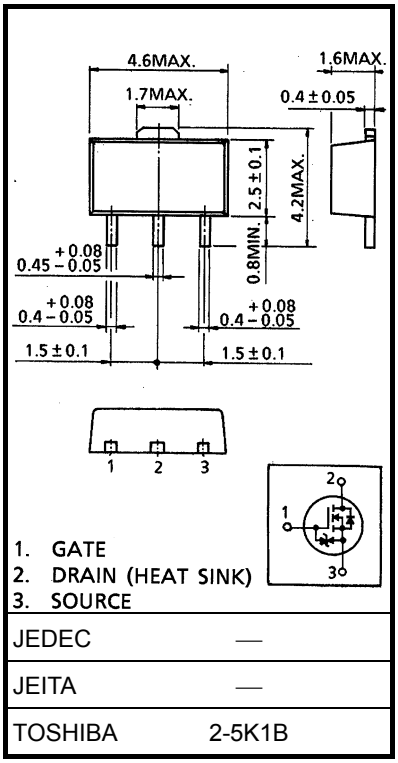
TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L^2−π−MOSVI)

2SK2964

Chopper Regulators, DC−DC Converters and Motor DriveApplications

- 4-V gate drive
- Low drain-source ON-resistance: $R_{DS\ (ON)}$ = 0.13 Ω (typ.)
- High forward transfer admittance: $|Y_{fs}|$ = 2.5 S (typ.)
- Low leakage current: I_{DSS} = 100 μA (max) (V_{DS} = 30 V)
- Enhancement mode: V_{th} = 0.8 to 2.0 V (V_{DS} = 10 V, I_D = 1 mA)

Unit: mm



JEDEC	—
JEITA	—
TOSHIBA	2-5K1B

Weight: 0.05 g (typ.)

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Drain−source voltage		V_{DSS}	30	V
Drain−gate voltage (R_{GS} = 20 kΩ)		V_{DGR}	30	V
Gate−source voltage		V_{GSS}	±20	V
Drain current	DC (Note 1)	I_D	2	A
	Pulse (Note 1)	I_{DP}	6	A
Drain power dissipation		P_D	0.5	W
Drain power dissipation (Note 2)		P_D	1.5	W
Single pulse avalanche energy (Note 3)		E_{AS}	56	mJ
Avalanche current		I_{AR}	2	A
Repetitive avalanche energy (Note 4)		E_{AR}	0.05	mJ
Channel temperature		T_{ch}	150	°C
Storage temperature range		T_{stg}	−55 to 150	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook (“Handling Precautions”/“Derating Concept and Methods”) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient	$R_{th\ (ch-a)}$	250	°C / W

Note 1: Ensure that the channel temperature does not exceed 150°C.

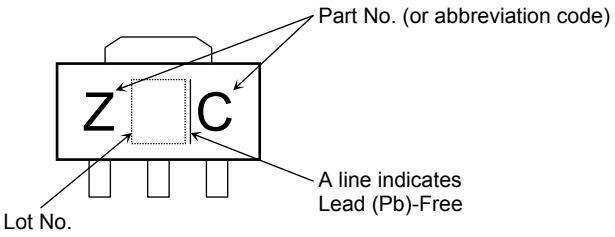
Note 2: Mounted on a ceramic substrate (25.4 mm × 25.4 mm × 0.8 mm)

Note 3: V_{DD} = 25 V, T_{ch} = 25°C (initial), L = 10 mH, R_G = 25 Ω, I_{AR} = 2 A

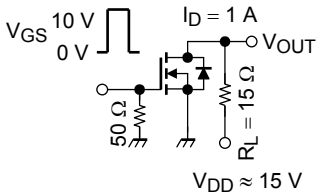
Note 4: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.
Handle with care.

Marking



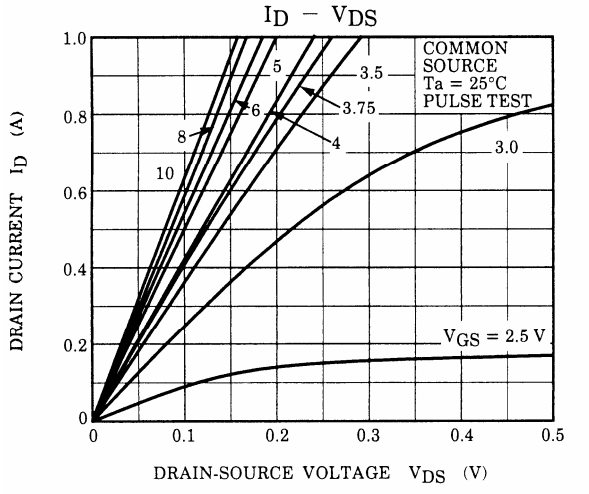
Electrical Characteristics (Ta = 25°C)

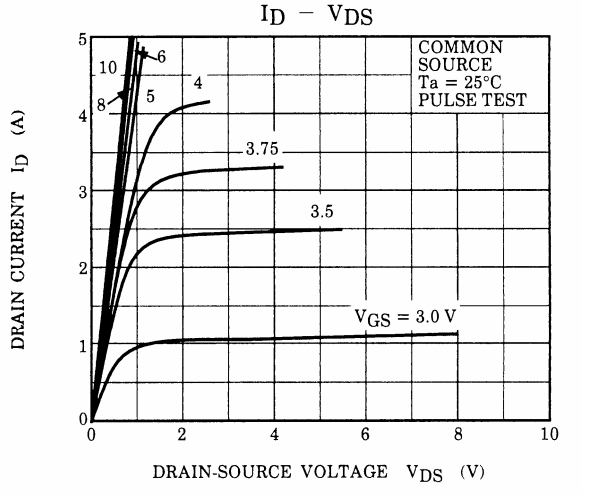
Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		I_{GSS}	V_{GS} = ±16 V, V_{DS} = 0 V	—	—	±10	μA
Drain cut−off current		I_{DSS}	V_{DS} = 30 V, V_{GS} = 0 V	—	—	100	μA
Drain−source breakdown voltage		$V_{(BR)\ DSS}$	I_D = 10 mA, V_{GS} = 0 V	30	—	—	V
Gate threshold voltage		V_{th}	V_{DS} = 10 V, I_D = 1 mA	0.8	—	2.0	V
Drain−source ON-resistance		$R_{DS\ (ON)}$	V_{GS} = 4 V, I_D = 1 A	—	0.18	0.25	Ω
			V_{GS} = 10 V, I_D = 1 A	—	0.13	0.18	
Forward transfer admittance		$\|Y_{fs}\|$	V_{DS} = 10 V, I_D = 1 A	1.2	2.5	—	S
Input capacitance		C_{iss}	V_{DS} = 10 V, V_{GS} = 0 V, f = 1 MHz	—	140	—	pF
Reverse transfer capacitance		C_{rss}		—	30	—	
Output capacitance		C_{oss}		—	80	—	
Switching time	Rise time	t_r		—	10	—	ns
	Turn−on time	t_{on}		—	15	—	
	Fall time	t_f		—	85	—	
	Turn−off time	t_{off}		—	195	—	
Total gate charge (gate−source plus gate−drain)		Q_g	V_{DD} ≈ 24 V, V_{GS} = 10 V, I_D = 2 A	—	5.8	—	nC
Gate−source charge		Q_{gs}		—	4.3	—	
Gate−drain (“miller”) Charge		Q_{gd}		—	1.5	—	

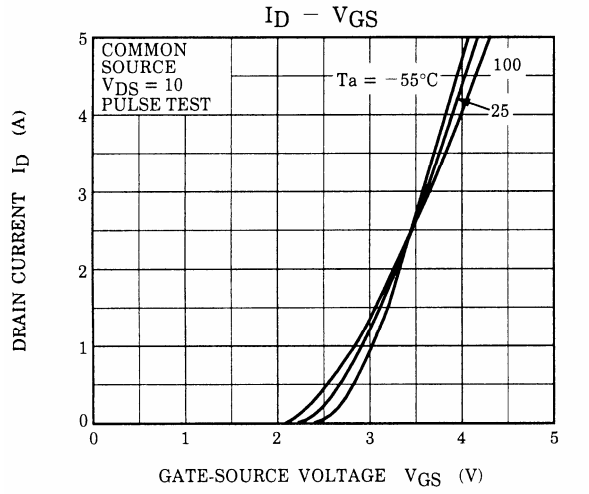
Duty ≤ 1%, t_w = 10 μs

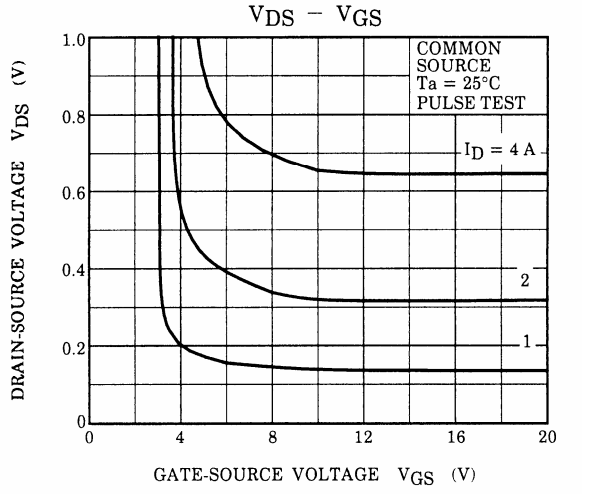
Source−Drain Ratings and Characteristics (Ta = 25°C)

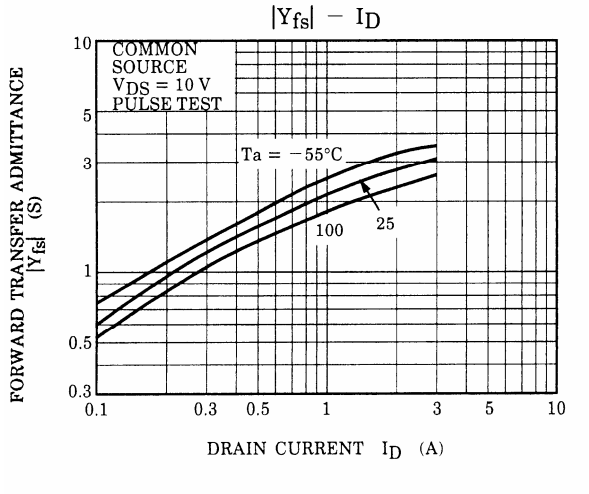
Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current (Note 1)	I_{DR}	—	—	—	2	A
Pulse drain reverse current (Note 1)	I_{DRP}	—	—	—	6	A
Forward voltage (diode)	V_{DSF}	I_{DR} = 2 A, V_{GS} = 0 V	—	—	−1.5	V
Reverse recovery time	t_{rr}	I_{DR} = 2 A, V_{GS} = 0 V, dI_{DR}/dt = 50 A/μs	—	50	—	ns
Reverse recovery charge	Q_{rr}		—	20	—	nC

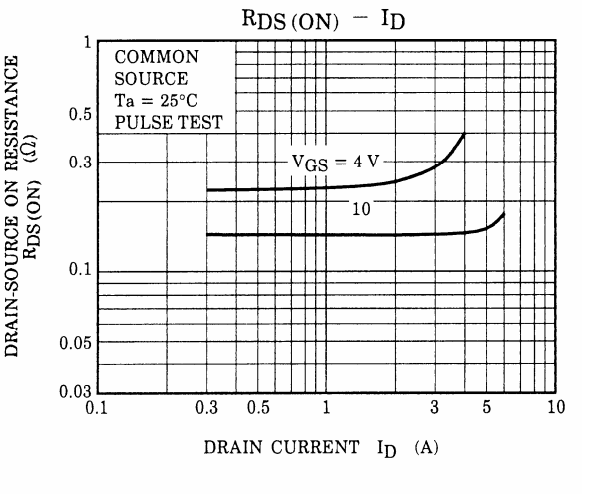

I_D – V_{DS}
COMMON SOURCE
Ta = 25°C
PULSE TEST
DRAIN CURRENT I_D (A)
DRAIN-SOURCE VOLTAGE V_{DS} (V)
V_{GS} = 2.5 V
3.0
3.5
3.75
4
5
6
8
10


I_D – V_{DS}
COMMON SOURCE
Ta = 25°C
PULSE TEST
DRAIN CURRENT I_D (A)
DRAIN-SOURCE VOLTAGE V_{DS} (V)
V_{GS} = 3.0 V
3.5
3.75
4
5
6
8
10

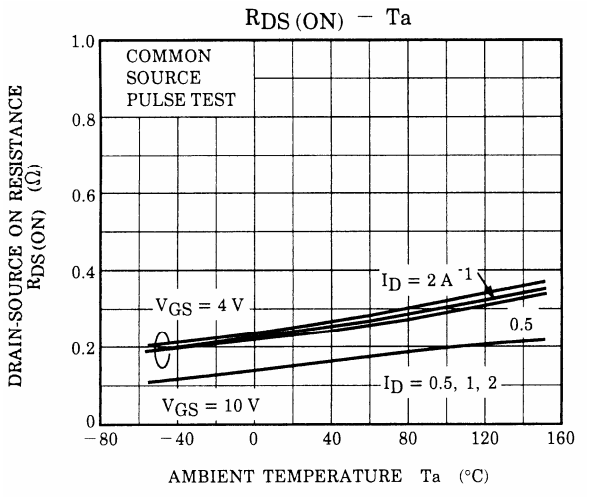

I_D – V_{GS}
COMMON SOURCE
V_{DS} = 10
PULSE TEST
Ta = −55°C
25
100
DRAIN CURRENT I_D (A)
GATE-SOURCE VOLTAGE V_{GS} (V)


V_{DS} – V_{GS}
COMMON SOURCE
Ta = 25°C
PULSE TEST
I_D = 4 A
2
1
DRAIN-SOURCE VOLTAGE V_{DS} (V)
GATE-SOURCE VOLTAGE V_{GS} (V)

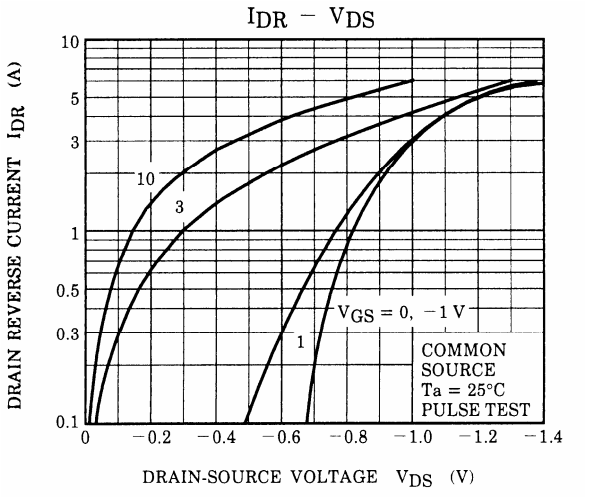

$|Y_{fs}|$ – I_D
COMMON SOURCE
V_{DS} = 10 V
PULSE TEST
Ta = −55°C
25
100
FORWARD TRANSFER ADMITTANCE $|Y_{fs}|$ (S)
DRAIN CURRENT I_D (A)


$R_{DS\,(ON)}$ – I_D
COMMON SOURCE
Ta = 25°C
PULSE TEST
V_{GS} = 4 V
10
DRAIN-SOURCE ON RESISTANCE $R_{DS\,(ON)}$ (Ω)
DRAIN CURRENT I_D (A)

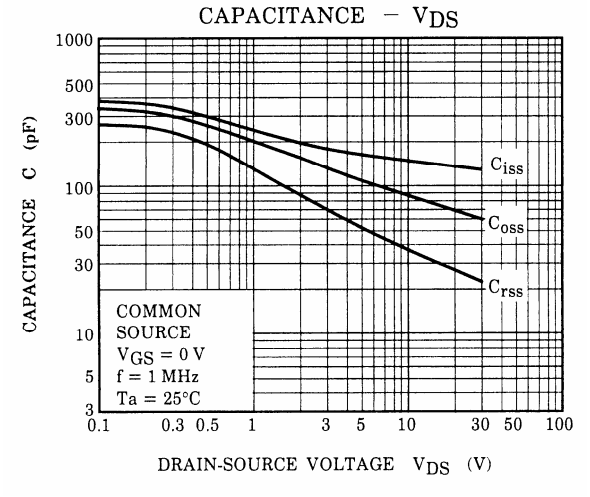
$R_{DS\,(ON)}$ – Ta



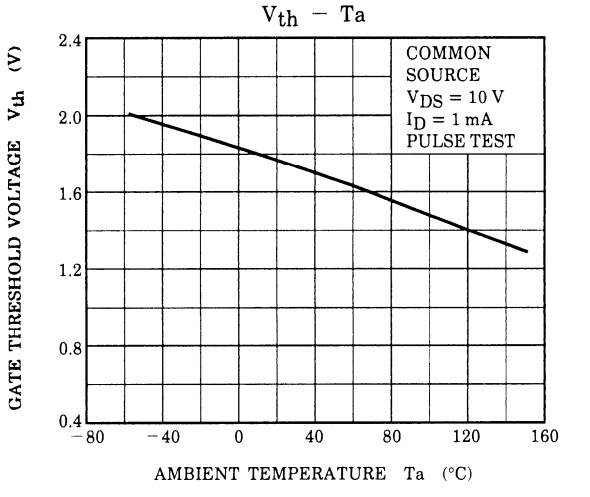
I_{DR} – V_{DS}



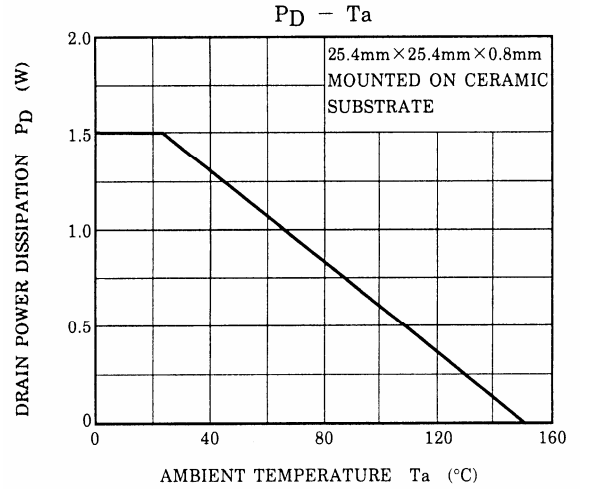
CAPACITANCE – V_{DS}



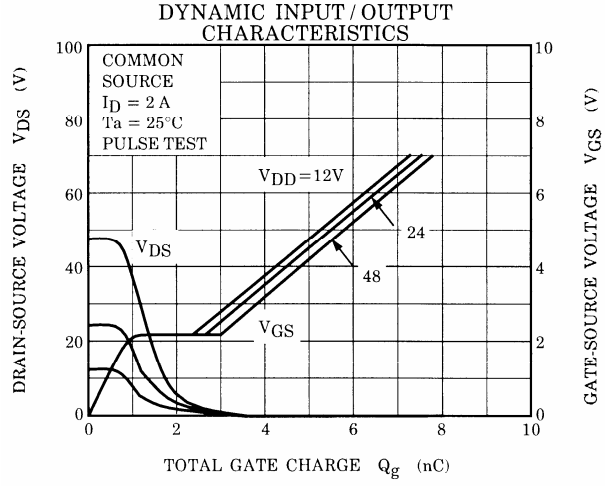
V_{th} – Ta



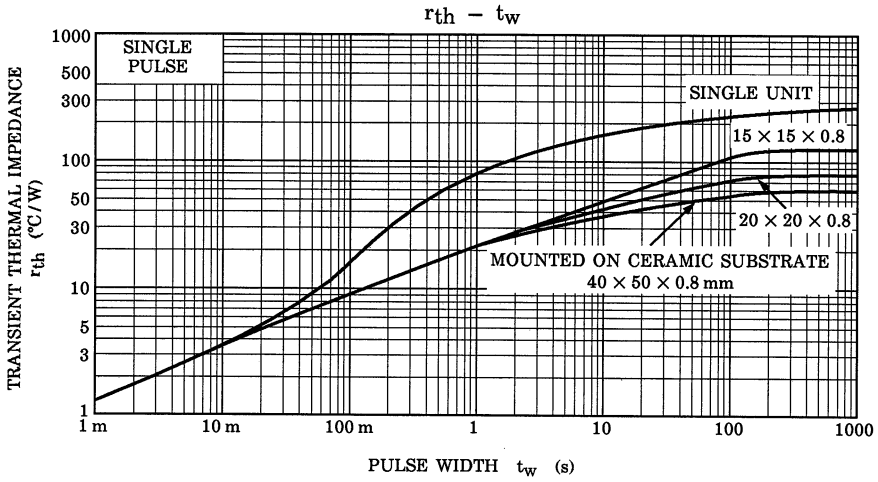
P_D – Ta



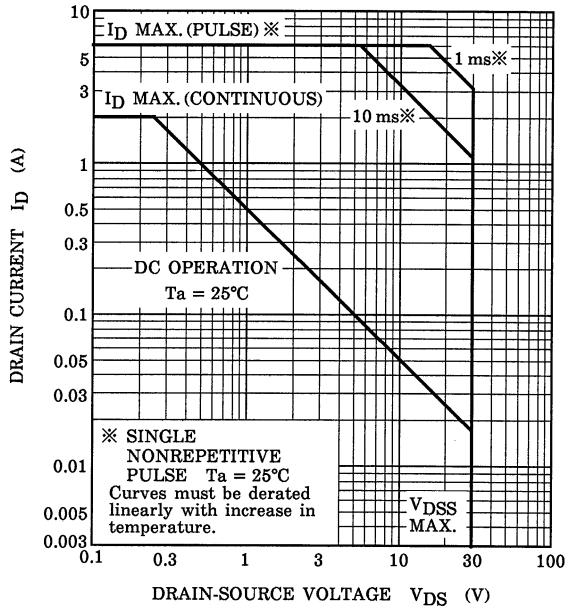
DYNAMIC INPUT / OUTPUT CHARACTERISTICS



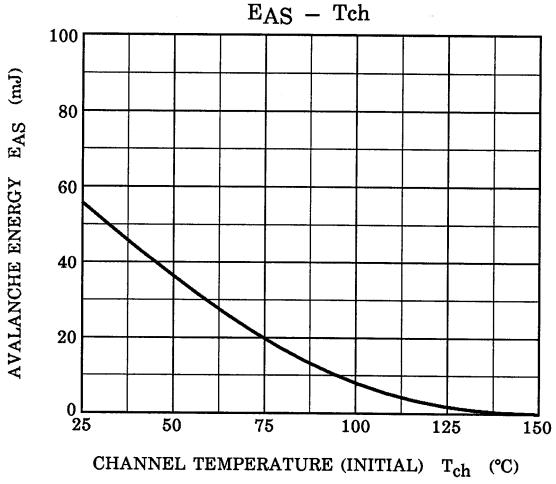
$r_{th} - t_w$

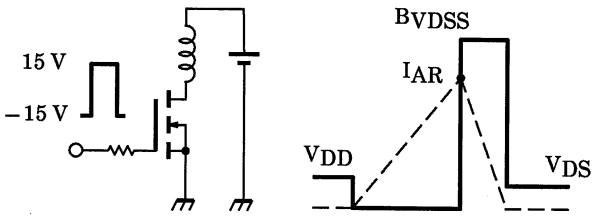


SAFE OPERATING AREA



E_{AS} – Tch





$R_G = 25\ \Omega$
$V_{DD} = 25$ V, L = 10 mH

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$

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20070701-EN GENERAL

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